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RF Exposure Evaluation Report

Report No.: CQASZ20240100023E-02
Applicant: Dongguan Jiajiatong Plastic Mould Co., Ltd
Address of Applicant: No. 10, Qiaojiao Middle Road, Pingshan 188 Industrial Zone, Tangxia Town, Dongguan City, Guangdong Province, China
Equipment Under Test (EUT):
Product: 5 in 1 Wireless charging
Model No.: JJT-C09
Test Model No.: JJT-C09
Brand Name: N/A
FCC ID: 2A2UK-JJT-C09
Standards: 47 CFR Part 1.1307
47 CFR Part 1.1310
KDB 680106 D01 RF Exposure Wireless Charging Base App v04r01
Date of Receipt: 2024-1-2
Date of Test: 2024-1-2 to 2024-1-8
Date of Issue: 2024-1-19
Test Result : **PASS***


*In the configuration tested, the EUT complied with the standards specified above

Tested By: 

(Joe Wang)

Reviewed By: 

(Timo Lei)

Approved By: 

(Jack Ai)



1 Version

Revision History Of Report

Report No.	Version	Description	Issue Date
CQASZ20240100023E-02	Rev.01	Initial report	2024-1-19

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3 General Information

3.1 Client Information

Applicant:	Dongguan Jiajiatong Plastic Mould Co., Ltd
Address of Applicant:	No. 10, Qiaojiao Middle Road, Pingshan 188 Industrial Zone, Tangxia Town, Dongguan City, Guangdong Province, China
Manufacturer:	Dongguan Jiajiatong Plastic Mould Co., Ltd
Address of Manufacturer:	No. 10, Qiaojiao Middle Road, Pingshan 188 Industrial Zone, Tangxia Town, Dongguan City, Guangdong Province, China
Factory:	Dongguan Jiajiatong Plastic Mould Co., Ltd
Address of Factory:	No. 10, Qiaojiao Middle Road, Pingshan 188 Industrial Zone, Tangxia Town, Dongguan City, Guangdong Province, China

3.2 General Description of EUT

Product Name:	5 in 1 Wireless charging
Model No.:	JJT-C09
Test Model No.:	JJT-C09
Software Version:	V2
Hardware Version:	V2
Power Supply:	Adapter: DC 9V 3A 12V 2.5A

3.3 Product Specification subjective to this standard

Equipment Category:	Non-ISM frequency
Operation Frequency range:	115kHz~205kHz,315KHz~330KHz
Modulation Type:	ASK
Antenna Type:	Induction coil
Antenna Gain:	0dBi
Power:	Output: 23W(Max)

Note:

1. In section 15.31(m), regards to the operating frequency range less 1 MHz.

3.4 Test Environment

Operating Environment:	
Temperature:	25.5 °C
Humidity:	53 % RH
Atmospheric Pressure:	1009 mbar
Test Mode:	
Mode a:	Keep the EUT Wireless Out Put for Wireless charge load 1 3W (MAX)
Mode b:	Keep the EUT Wireless Out Put for Apple headset 5W (MAX)
Mode c:	Keep the EUT Wireless Out Put for Wireless charge load 2 5W
Mode d:	Keep the EUT Wireless Out Put for Wireless charge load 2 7.5W
Mode e:	Keep the EUT Wireless Out Put for Wireless charge load 2 10W
Mode f:	Keep the EUT Wireless Out Put for Wireless charge load 2 15W (MAX)
Mode g:	Keep the EUT Wireless Out Put for Wireless charge load 1+for Apple headset +for Wireless charge load 2 23W (Total MAX)
Note: The above test modes all include full load,empty load,and half load, The worst-case state reflected in this report is the fully loaded state	

3.5 Description of Support Units

The EUT has been tested with associated equipment below.

1) Support equipment

Description	Manufacturer	Model No.	Certification	Supplied by
Adapter	/	LPL-C010050200Z	/	CQA
Wireless charge load 1	/	/	/	CQA
Wireless charge load 2	/	/	/	CQA
Apple headset	Apple	/	/	CQA

2) Cable

Cable No.	Description	Manufacturer	Cable Type/Length	Supplied by
/	/	/	/	/

3.6 Test Location

Shenzhen Huaxia Testing Technology Co., Ltd.

1F., Block A of Tongsheng Technology Building, Huahui Road, Dalang Street, Longhua District, Shenzhen, China

3.7 Test Facility

• **A2LA (Certificate No. 4742.01)**

Shenzhen Huaxia Testing Technology Co., Ltd., Shenzhen EMC Laboratory is accredited by the American Association for Laboratory Accreditation(A2LA). Certificate No. 4742.01.

• **FCC Registration No.: 522263**

Shenzhen Huaxia Testing Technology Co., Ltd., Shenzhen EMC Laboratory has been registered and fully described in a report filed with the (FCC) Federal Communications Commission. The acceptance letter from the FCC is maintained in our files. Registration No.:522263

3.8 Equipment List

Test Equipment	Manufacturer	Model No.	Instrument No.	Calibration Date	Calibration Due Date
Broadband Field Meter	Narda Safety Test Solutions GmbH	NBM-520	SB9873	2023/9/8	2024/9/7
Magnetic field probe	HIOKI	3470	SB9058/04	2023/9/8	2024/9/7
E-field probe	Narda	EF0391	SB9059	2023/9/8	2024/9/7

4 RF Exposure Evaluation

4.1 RF Exposure Compliance Requirement

4.1.1 Limits

According to FCC Part1.1310: The criteria listed in the following table shall be used to evaluate the environment impact of human exposure to radio frequency (RF) radiation as specified in part1.1307(b)

TABLE 1—LIMITS FOR MAXIMUM PERMISSIBLE EXPOSURE (MPE)

Frequency range (MHz)	Electric field strength (V/m)	Magnetic field strength (A/m)	Power density (mW/cm ²)	Averaging time (minutes)
(A) Limits for Occupational/Controlled Exposures				
0.3–3.0	614	1.63	*(100)	6
3.0–30	1842/f	4.89/f	*(900/f ²)	6
30–300	61.4	0.163	1.0	6
300–1500	f/300	6
1500–100,000	5	6
(B) Limits for General Population/Uncontrolled Exposure				
0.3–1.34	614	1.63	*(100)	30
1.34–30	824/f	2.19/f	*(180/f ²)	30
30–300	27.5	0.073	0.2	30
300–1500	f/1500	30
1500–100,000	1.0	30

Note 1: f = frequency in MHz ; *Plane-wave equivalent power density

Note 2: For the applicable limit, see FCC 1.1310, 680106 D01 RF Exposure Wireless Charging Apps v04

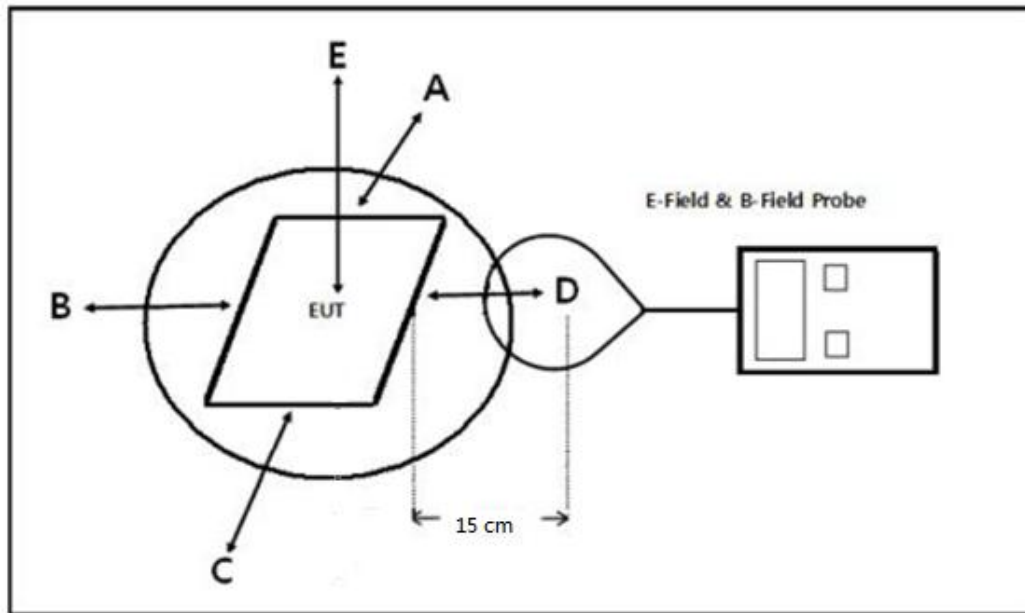
Note 3: Emissions between 100 kHz to 300 kHz should be assessed versus the limits at 300 kHz in Table 1 of Section 1.1310: 614 V/m and 1.63 A/m. A KDB inquiry is required to determine the applicable exposure limits below 100 kHz.

Note 4: The aggregate H-field strengths at 15 cm surrounding the device and 20 cm above the top surface from all simultaneous transmitting coils are demonstrated to be less than 50% of the MPE limit .

4.1.2 Test Procedure

For devices designed for typical desktop applications, such a wireless charging pads, RF exposure evaluation should be conducted assuming a user separation distance of 20 cm(Top) and 15cm(Edge). E and H field strength measurements or numerical modeling may be used to demonstrate compliance. Measurements should be made from all sides and the top of the primary/client pair, with the 20 cm(Top) and 15cm(Edge) measured from the center of the probe(s) to the edge of the device.

4.1.3 Test Setup



Note: Position A: Front of EUT; Position B: Left of EUT; Position C: back of EUT; Position D: Right of EUT; Position E: Top of EUT(20 cm measure distance);

4.1.4 Test Results

The EUT does comply with item 5 KDB680106 D01 v04r01.

- (1) The power transfer frequency is below 1 MHz.
- (2) The output power from each transmitting element (e.g., coil) is less than or equal to 15 watts.
- (3) A client device providing the maximum permitted load is placed in physical contact with the transmitter (i.e., the surfaces of the transmitter and client device enclosures need to be in physical contact)
- (4) Only § 2.1091-Mobile exposure conditions apply (i.e., this provision does not cover § 2.1093-Portable exposure conditions).
- (5) The E-field and H-field strengths, at and beyond 20 cm surrounding the device surface, are demonstrated to be less than 50% of the applicable MPE limit, per KDB447498, Table 1. These measurements shall be taken along the principal axes of the device, with one axis oriented along the direction of the estimated maximum field strength, and for three points per axis or until a 1/d (inverse distance from the emitter structure) field strength decay is observed. Symmetry considerations may be used for test reduction purposes. The device shall be operated in documented worst-case compliance scenarios (i.e., the ones that lead to the maximum field components), and while all the radiating structures (e.g., coils or antennas) that by design can simultaneously transmit are energized at their nominal maximum power.
- (6) For systems with more than one radiating structure, the conditions specified in (5) must be met when the system is fully loaded (i.e., clients absorbing maximum power available), and with all the radiating structures operating at maximum power at the same time, as per design conditions. If the design allows one or more radiating structures to be powered at a higher level while other radiating structures are not powered, then those cases must be tested as well. For instance, a device may use three RF coils powered at 5 W, or one coil powered at 15 W: in this case, both scenarios shall be tested.

Test condition: Mode b

E-field strength test result:

Frequency Range	Probe Position A (V/m)	Probe Position B (V/m)	Probe Position C (V/m)	Probe Position D (V/m)	Probe Position E (V/m)	Limit (V/m)
117.25kHz	3.58	2.79	2.82	1.69	2.81	614

H-field strength test result:

Frequency Range	Probe Position A (A/m)	Probe Position B (A/m)	Probe Position C (A/m)	Probe Position D (A/m)	Probe Position E (A/m)	Limit (A/m)
117.25kHz	0.38	0.28	0.22	0.36	0.31	1.63

Test condition: Mode f

E-field strength test result:

Frequency Range	Probe Position A (V/m)	Probe Position B (V/m)	Probe Position C (V/m)	Probe Position D (V/m)	Probe Position E (V/m)	Limit (V/m)
121.06kHz	3.58	2.82	2.88	1.63	2.91	614

H-field strength test result:

Frequency Range	Probe Position A (A/m)	Probe Position B (A/m)	Probe Position C (A/m)	Probe Position D (A/m)	Probe Position E (A/m)	Limit (A/m)
121.06kHz	0.27	0.30	0.25	0.31	0.29	1.63

Test condition: Mode a

E-field strength test result:

Frequency Range	Probe Position A (V/m)	Probe Position B (V/m)	Probe Position C (V/m)	Probe Position D (V/m)	Probe Position E (V/m)	Limit (V/m)
319.20kHz	3.51	2.74	2.81	1.57	2.82	614

H-field strength test result:

Frequency Range	Probe Position A (A/m)	Probe Position B (A/m)	Probe Position C (A/m)	Probe Position D (A/m)	Probe Position E (A/m)	Limit (A/m)
319.20kHz	0.34	0.31	0.24	0.30	0.28	1.63

Test condition: Mode g

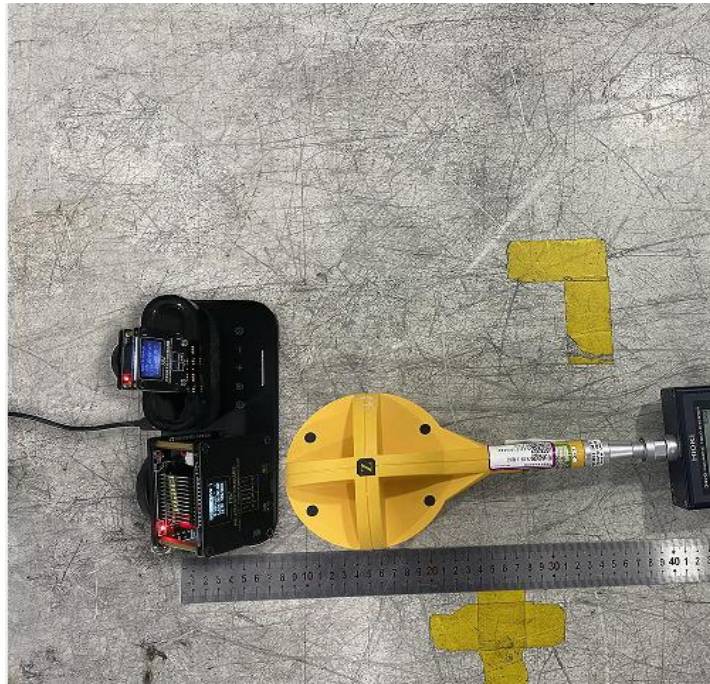
E-field strength test result:

Frequency Range	Probe Position A (V/m)	Probe Position B (V/m)	Probe Position C (V/m)	Probe Position D (V/m)	Probe Position E (V/m)	Limit (V/m)
/	3.45	2.72	2.80	1.54	2.78	614

H-field strength test result:

Frequency Range	Probe Position A (A/m)	Probe Position B (A/m)	Probe Position C (A/m)	Probe Position D (A/m)	Probe Position E (A/m)	Limit (A/m)
/	0.33	0.33	0.22	0.29	0.27	1.63

APPENDIX A: PHOTOGRAPHS OF TEST SETUP



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